

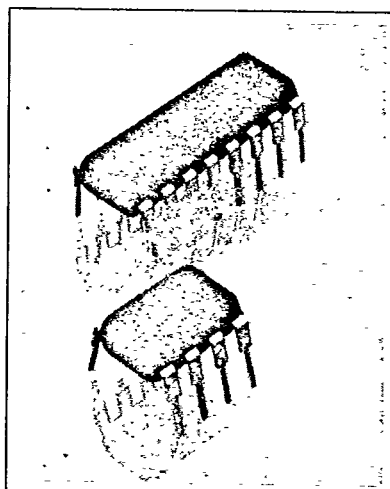
SIEMENS

T-41-83

DUAL CHANNEL ILD1/2/5

QUAD CHANNEL ILQ1/2/5

PHOTOTRANSISTOR OPTOCOUPLER

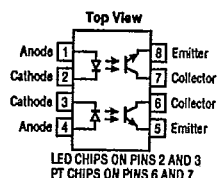
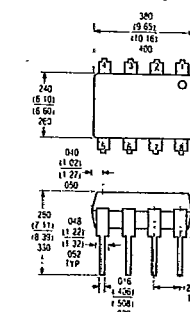


FEATURES

- **Current Transfer Ratio @ $I_F = 10 \text{ mA}$**
 $ILD/Q1 - 20\% \text{ Min.}$
 $ILD/Q2 - 100\% \text{ Min.}$
 $ILD/Q5 - 50\% \text{ Min.}$
- **High Collector-Emitter Voltage**
 $ILD/Q1 - BV_{CEO} = 50 \text{ V}$
 $ILD/Q2, ILD/Q5 - BV_{CEO} = 70 \text{ V}$
- **Field-Effect Stable by Transparent Ion Shield (TRIOS)**
- **Double Molded Package Offers Withstand Test Voltage**
 $7500 \text{ VAC}_{PEAK}, 1 \text{ sec.}$
 $4420 \text{ VAC}_{RMS}, 1 \text{ min.}$
- **UL Approval #E52744**
-  **VDE Approval #0883**

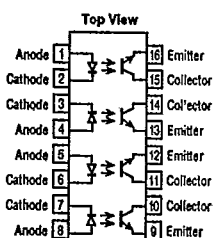
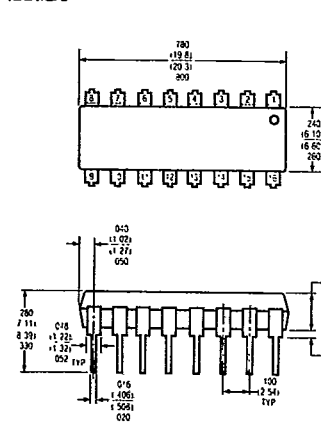
Package Dimensions in Inches (mm)

ILD1/2/5



LED CHIPS ON PINS 2 AND 3
PT CHIPS ON PINS 6 AND 7

ILQ1/2/5



LED CHIPS ON PINS 2, 3, 6, 7
PT CHIPS ON PINS 10, 11, 14, 15

DESCRIPTION

The ILD/Q1/2/5 are optically coupled isolated pairs employing GaAs infrared LEDs and silicon NPN phototransistor. Signal information, including a DC level, can be transmitted by the drive while maintaining a high degree of electrical isolation between input and output. The ILD/Q1/2/5 are especially designed for driving medium-speed logic and can be used to eliminate troublesome ground loop and noise problems. Also these couplers can be used to replace relays and transformers in many digital interface applications such as CRT modulation. The ILD1/2/5 has two isolated channels in a single DIP package and the ILQ1/2/5 has four isolated channels per package.

See Appnote 45, "How to Use Optocoupler Normalized Curves."

Maximum Ratings

Emitter	
Reverse Voltage	6 V
Forward Current	100 mA
Surge Current	2.5 A
Power Dissipation	200 mW
Derate Linearly from 25°C	2.6 mW/°C
Detector	
Collector-Emitter Reverse Voltage	
ILD/Q1	50 V
ILD/Q2, ILD/Q5	70 V
Emitter-Base Reverse Voltage	7 V
Collector-Base Reverse Voltage	70 V
Collector Current	50 mA
Collector Current ($t < 1$ ms)	400 mA
Power Dissipation	200 mW
Derate Linearly from 25°C	2.6 mW/°C
Package	
Storage Temperature	-40°C to +150°C
Operating Temperature	-40°C to +100°C
Junction Temperature	100°C
Soldering Temperature (in a 2 mm distance from case bottom)	260°C
Package Power Dissipation	250 mW
Derate Linearly from 25°C	3.3 mW/°C
UL Withstand Test Voltage (PK) ($t = 1$ sec.)	7500 VDC/5300 VAC
VDE Isolation Test Voltage	
In Accordance with DIN 57883/6.80	5300 VDC/3750 VAC
Creepage Path	8 min mm
Clearance Path	7 min mm
Tracking Index According to VDE 0303	KB 100/A
Working Voltage	1700 VAC
Insulation Resistance	$10^{11} \Omega$

Characteristics

	Symbol	Min.	Typ.	Max.	Unit
Emitter					
Forward Voltage ($I_F = 60$ mA)	V_F		1.25	1.65	V
Breakdown Voltage ($I_R = 10$ μ A)	V_{BR}	6	30		V
Reverse Current ($V_R = 6$ V)	I_R		0.01	10	μ A
Capacitance ($V_R = 0$ V, $f = 1$ MHz)	C_0		40		pF
Thermal Resistance Junction to Lead	R_{thL}		750		°C/W
Detector					
Capacitance ($V_{CE} = 5$ V, $f = 1$ MHz)	C_{CE}		6.8		pF
($V_{CB} = 5$ V, $f = 1$ MHz)	C_{CB}		8.5		pF
($V_{EB} = 5$ V, $f = 1$ MHz)	C_{EB}		11		pF
Collector-Emitter Leakage Current ($V_{CE} = 10$ V)	I_{CEO}		5	50	nA
Collector-Emitter Saturation Voltage ($I_{CE} = 1$ mA, $I_B = 20$ μ A)	$V_{CE(SAT)}$		0.25	0.4	
Base-Emitter Voltage ($V_{CE} = 10$ V, $I_B = 20$ μ A)	V_{BE}		0.65		V
DC Forward					
Current Gain ($V_{CE} = 10$ V, $I_B = 20$ μ A)	HFE	200	650	1800	
Saturated DC Forward Current Gain ($V_{CE} = 0.4$ V, $I_B = 20$ μ A)	HFE _{SAT}	120	400	600	
Thermal Resistance Junction to Lead	R_{thL}		500		°C/W

Characteristics (Cont.)

	Symbol	Min.	Typ.	Max.	Unit
Package Transfer Characteristics					
ILD/Q1					
Saturated Current					
Transfer Ratio (Collector-Emitter) ($I_F = 10$ mA, $V_{CE} = 0.4$ V)					
	CTR _{CE(SAT)}		75		%
Current Transfer Ratio (Collector-Emitter) ($I_F = 10$ mA, $V_{CE} = 10$ V)					
	CTR _{CE}	20	80	300	%
Current Transfer Ratio (Collector-Base) ($I_F = 10$ mA, $V_{CB} = 9.3$ V)					
	CTR _{CB}		0.25		%
ILD/Q2					
Saturated Current					
Transfer Ratio (Collector-Emitter) ($I_F = 10$ mA, $V_{CE} = 0.4$ V)					
	CTR _{CE(SAT)}		170		%
Current Transfer Ratio (Collector-Emitter) ($I_F = 10$ mA, $V_{CE} = 10$ V)					
	CTR _{CE}	100	200	500	%
Current Transfer Ratio ($I_F = 10$ mA, $V_{CB} = 9.3$ V)					
	CTR _{CB}		0.35		%
ILD/Q5					
Saturated Current					
Transfer Ratio (Collector-Emitter) ($I_F = 10$ mA, $V_{CE} = 0.4$ V)					
	CTR _{CE(SAT)}		100		%
Current Transfer Ratio (Collector-Emitter) ($I_F = 10$ mA, $V_{CE} = 10$ V)					
	CTR _{CE}	50	130	400	%
Current Transfer Ratio ($I_F = 10$ mA, $V_{CB} = 9.3$ V)					
	CTR _{CB}		0.3		%

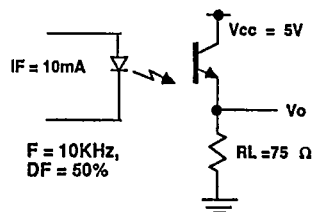
Isolation and Insulation

Common Mode Rejection					
Output High ($V_{CM} = 50 V_{RFP}$, $R_L = 1$ k Ω , $I_F = 0$ mA)					
	CMH		5000		V/ μ s
Common Mode Rejection					
Output Low ($V_{CM} = 50 V_{RFP}$, $R_L = 1$ k Ω , $I_F = 10$ mA)					
	CML		5000		V/ μ s
Common Mode					
Coupling Capacitance					
	C_{CM}		0.01		pF
Package Capacitance ($V_{LO} = 0$ V, $f = 1$ MHz.)					
	C_{LO}	0.8			pF
Insulation Resistance ($V_{LO} = 500$ V)					
	R_s	5×10^9	10^{14}		Ω
Dielectric Leakage Current ($V_{LO} = 4420$ AC (rms), 1 min., 60 Hz)					
	I_{LO}		3.3	10	μ A
(V _{LO} = 6250 VDC, 1 min.)					
			0.5	10	μ A
(V _{LO} = 5304 AC (rms), 1 sec., 60 Hz)					
			4	10	μ A
(V _{LO} = 7500 VDC, 1 sec.)					
			0.6	12	μ A

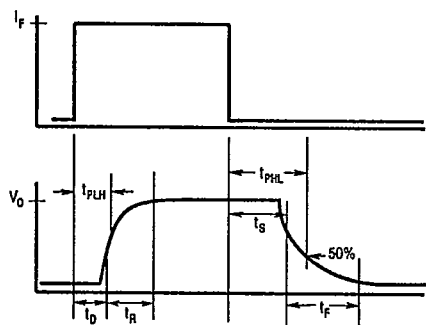
Optocouplers
(Optoisolators)

SWITCHING TIMES

Non-Saturated Switching



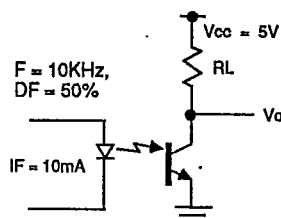
Non-Saturated Switching Timing



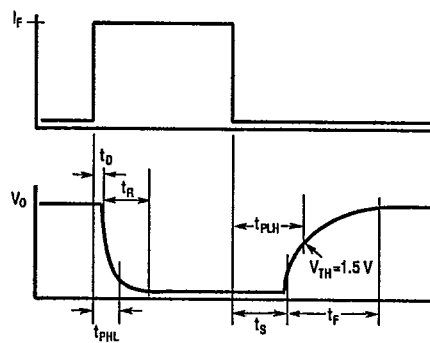
Characteristic		ILD/Q1 $I_F=20\text{ mA}$	ILD/Q2 $I_F=5\text{ mA}$	ILD/Q5 $I_F=10\text{ mA}$	Unit
Delay	T_D	0.8	1.7	1.7	μs
Rise Time ($V_{CC}=5\text{ V}$)	t_R	1.9	2.6	2.6	μs
Storage ($R_L=75\ \Omega$)	t_S	0.2	0.4	0.4	μs
Fall Time	t_F	1.4	2.2	2.2	μs
Propagation H-L (50% of V_{PP})	t_{PLH}	0.7	1.2	1.1	μs
Propagation L-H	t_{PHL}	1.4	2.3	2.5	μs

Saturated Switching

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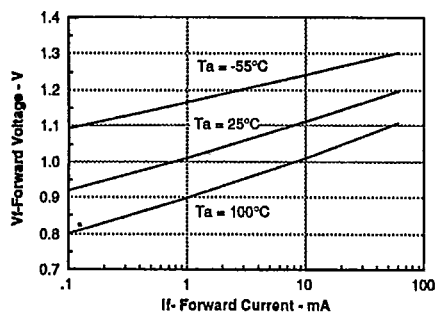


Saturated Switching Timing

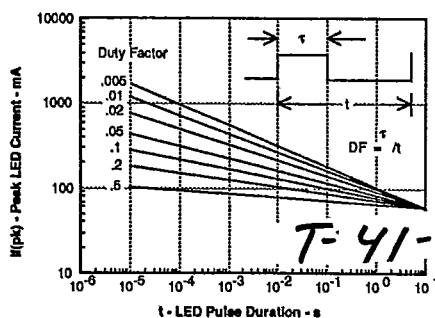


Characteristic		ILD/Q1 $I_F=20\text{ mA}$	ILD/Q2 $I_F=5\text{ mA}$	ILD/Q5 $I_F=10\text{ mA}$	Unit
Delay	T_D	0.8	1	1.7	μs
Rise Time ($V_{CE}=0.4\text{ V}$)	t_R	1.2	2	7	μs
Storage ($R_L=1\text{ k}\Omega$)	t_S	7.4	5.4	4.6	μs
Fall Time ($V_{CC}=5\text{ V}$)	t_F	7.6	13.5	20	μs
Propagation H-L ($V_{TH}=1.5\text{ V}$)	t_{PLH}	1.6	5.4	2.6	μs
Propagation L-H	t_{PHL}	8.6	7.4	7.2	μs

Forward voltage versus forward current

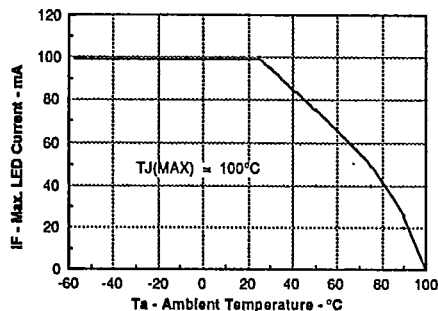


Peak LED current versus duty factor, Tau

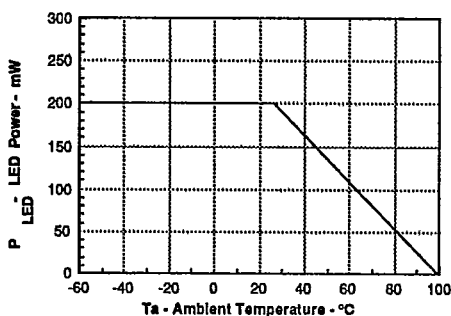


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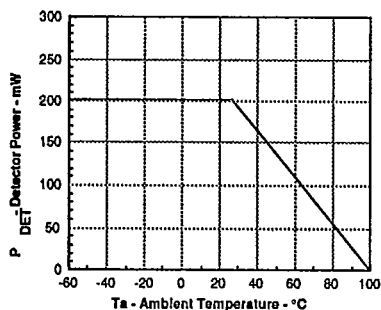
Maximum LED current versus ambient temperature



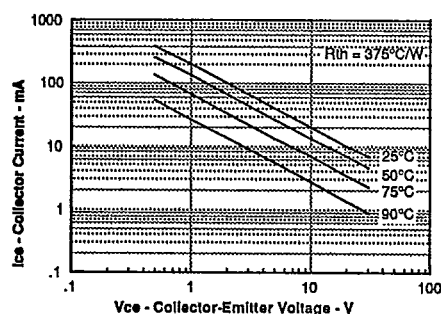
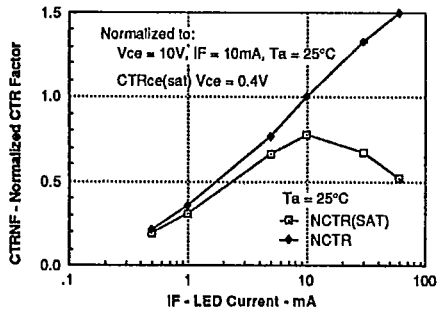
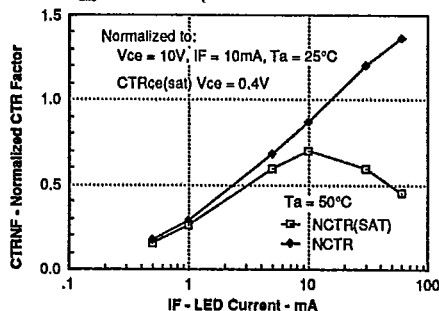
Maximum LED power dissipation

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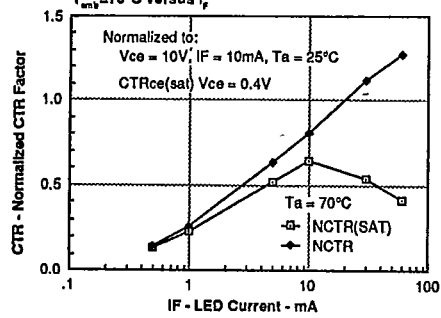
Maximum detector power dissipation



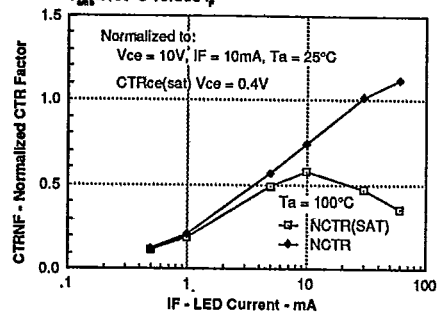
Maximum collector current versus collector voltage

Normalization factor for non-saturated and saturated CTR
 $T_{amb} = 25^\circ\text{C}$ versus I_f Normalization factor for non-saturated and saturated CTR
 $T_{amb} = 50^\circ\text{C}$ versus I_f 

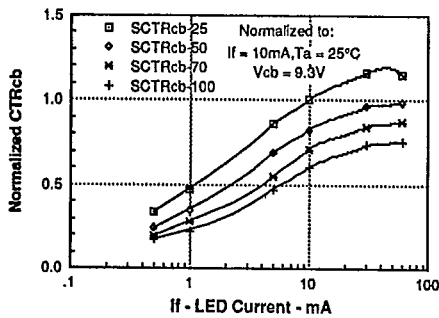
Normalization factor for non-saturated and saturated CTR
 $T_{amb} = 70^\circ\text{C}$ versus I_F



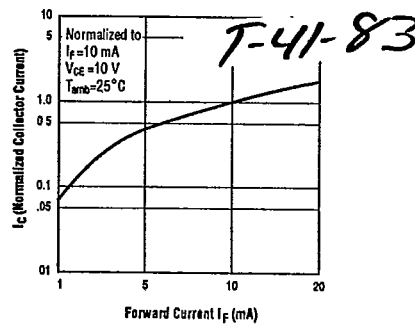
Normalization factor for non-saturated and saturated CTR
 $T_{amb} = 100^\circ\text{C}$ versus I_F



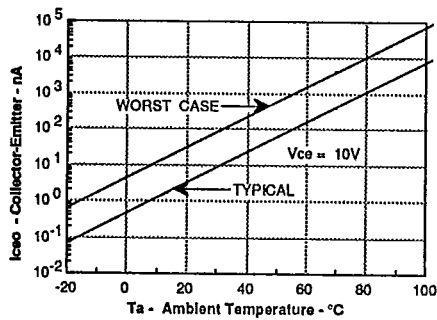
Normalized CTR_{cb} versus LED Current



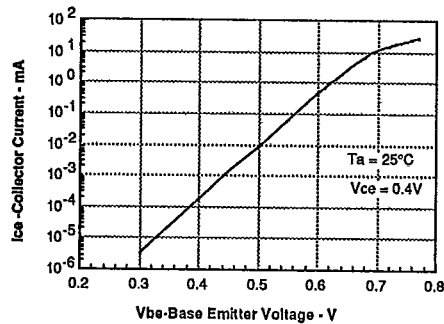
Collector current versus diode forward current



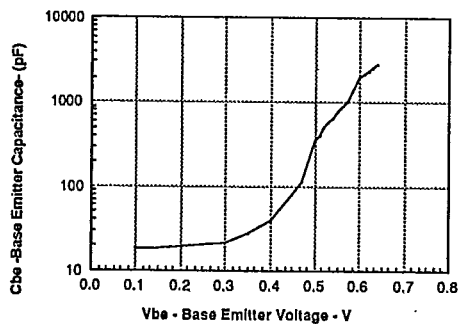
Collector-emitter leakage versus temperature



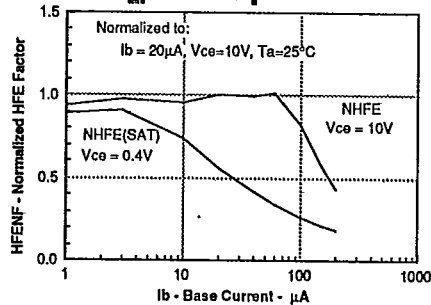
Collector current versus base voltage

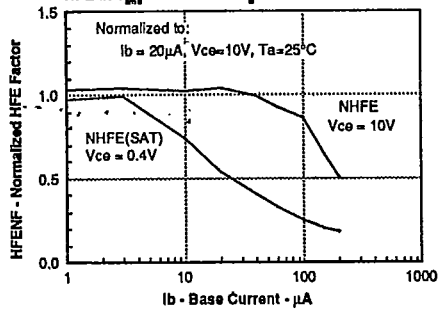
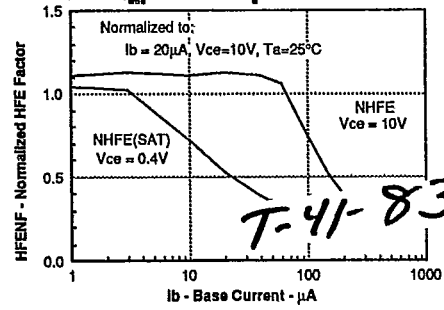


C_{be} versus V_{be}

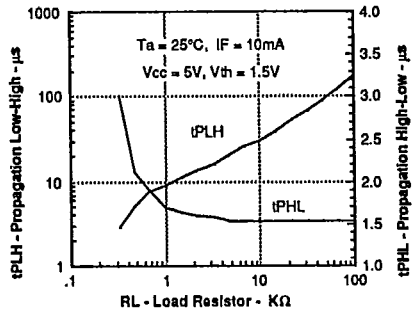


Normalization factor for non-saturated and saturated HFE at $T_{amb} = 25^\circ\text{C}$ versus I_b

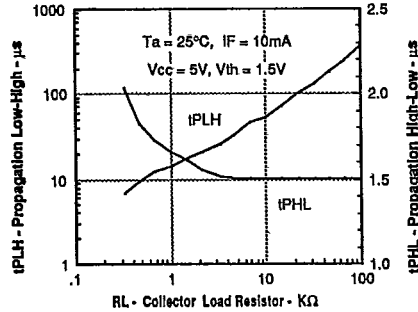


Normalization factor for non-saturated and saturated HFE at $T_{amb}=50^{\circ}\text{C}$ versus I_b Normalization factor for non-saturated and saturated HFE at $T_{amb}=70^{\circ}\text{C}$ versus I_b 

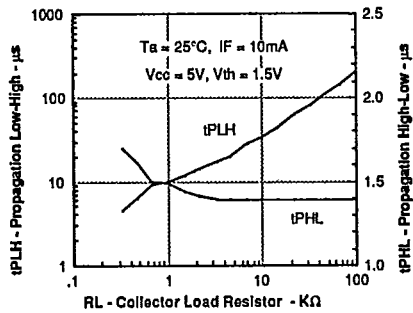
ILD/Q1 propagation delay versus collector load resistor



ILD/Q2 propagation delay versus collector load resistor



ILD/Q5 propagation delay versus collector load resistor

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